

PAUL SCHERRER INSTITUT



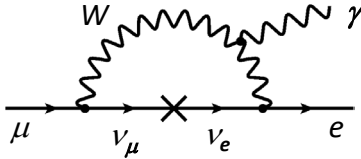
Hajime Nishiguchi, KEK, and Malte Hildebrandt, PSI  
on behalf of the MEG Collaboration

# HV stability and aging phenomena observed in the drift chamber system of the MEG experiment

3<sup>rd</sup> International Conference on Detector Stability and Aging Phenomena in Gaseous Detectors  
CERN, 07.11.2023

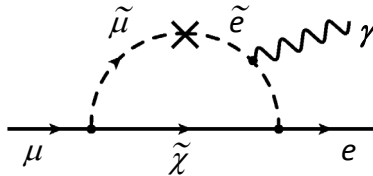
# Charged Lepton Flavour Violation

- charged lepton flavour violating (cLFV) decay  $\mu^+ \rightarrow e^+ \gamma$  not yet observed
- Standard Model (SM): forbidden decay
- Standard Model with  $\nu$  masses and oscillations: strongly suppressed due to small  $\nu$  masses



$$\text{BR}(\mu^+ \rightarrow e^+ \gamma) \approx 10^{-54}$$

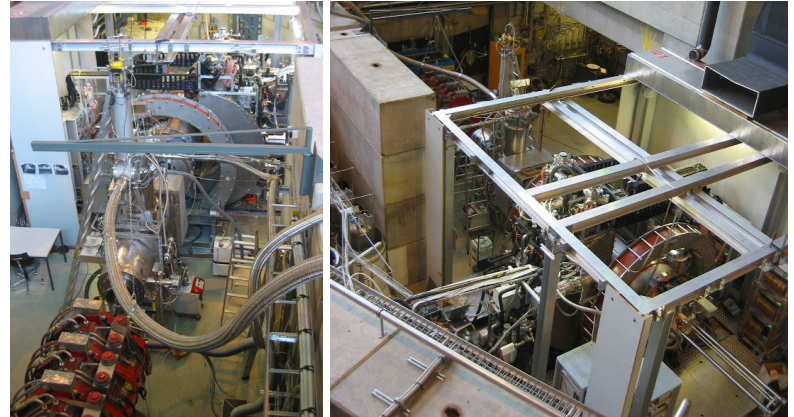
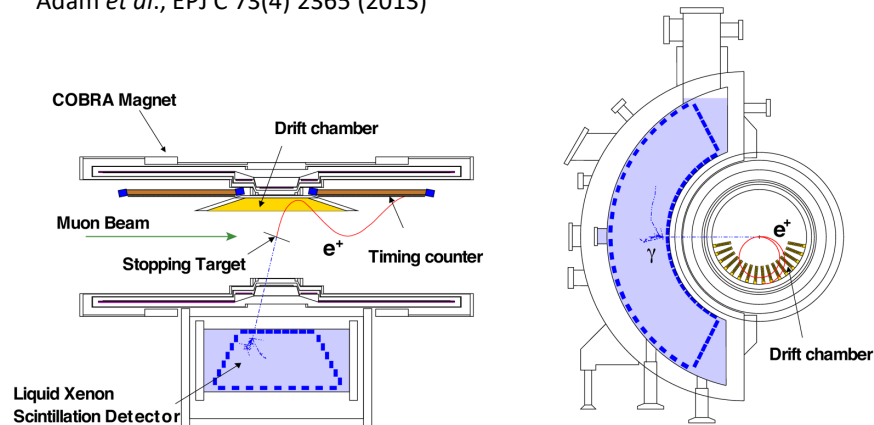
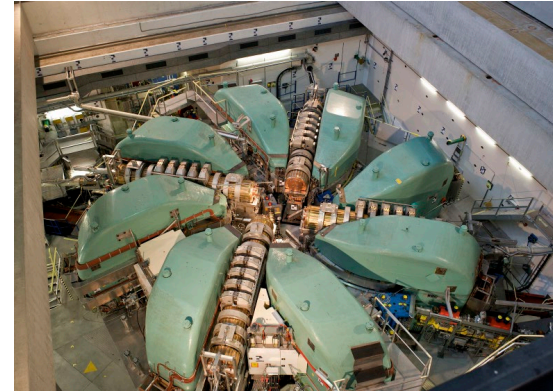
- Beyond Standard Model (BSM) theories: enhanced probability due to mixing of new particles



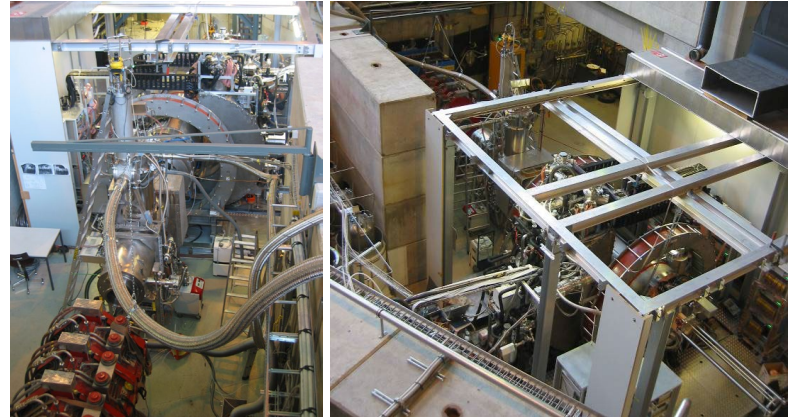
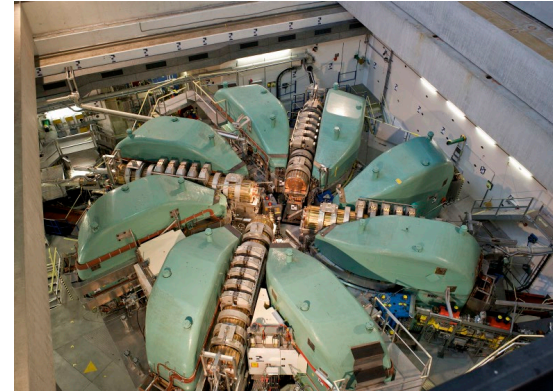
$$\text{BR}(\mu^+ \rightarrow e^+ \gamma) \gg 10^{-54} \quad (10^{-11} - 10^{-14})$$

→ experimental observation of  $\mu^+ \rightarrow e^+ \gamma$  is clear signature of “New Physics” beyond the SM

- search for cLFV decay  $\mu \rightarrow e + \gamma$
- located at CHRISP facility @ Paul Scherrer Institut (PSI)
  - p-cyclotron: 590 MeV, 2.4 mA ( $\rightarrow$ 1.4 MW)
  - $\pi$ E5: most intense DC low momentum (28 MeV/c) muon beam in the world: intensity  $O(10^8 \mu/s)$
- dedicated detector design to measure the observables characterising the  $\mu^+ \rightarrow e^+ \gamma$  event:  $E_\gamma, E_e, t_{e\gamma}, \vartheta_{e\gamma}, \varphi_{e\gamma}$   
Adam *et al.*, EPJ C 73(4) 2365 (2013)



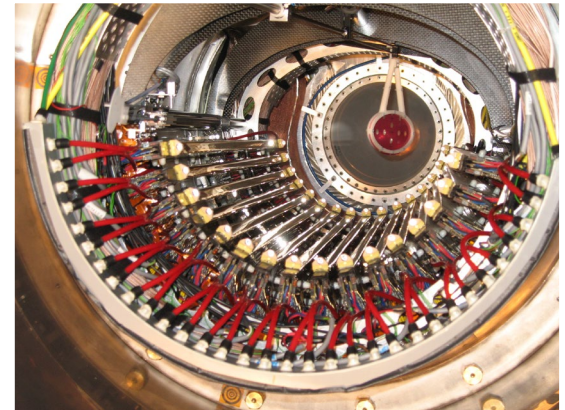
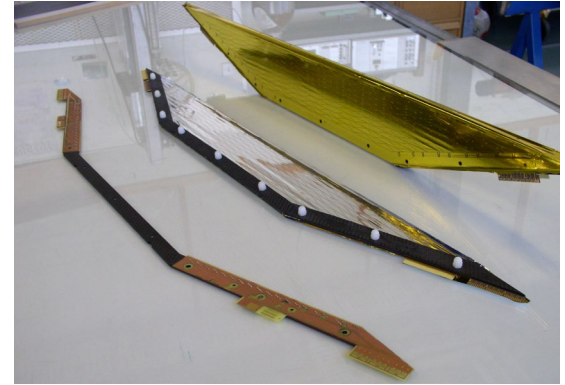
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- MEG:
  - analysis of full data sample 2009-2013  
BR ( $\mu^+ \rightarrow e^+ \gamma$ ) <  $4.2 \cdot 10^{-13}$  (90% CL)  
Baldini *et al.*, EPJ C 76(1), 434 (2016)
- MEG II:
  - analysis of data sample 2021 & MEG  
BR ( $\mu^+ \rightarrow e^+ \gamma$ ) <  $3.1 \cdot 10^{-13}$  (90% CL)  
arXiv:2310.12614 [hep-ex]
  - goal: final sensitivity  $10^{-14}$  level





# Drift Chamber System @ MEG

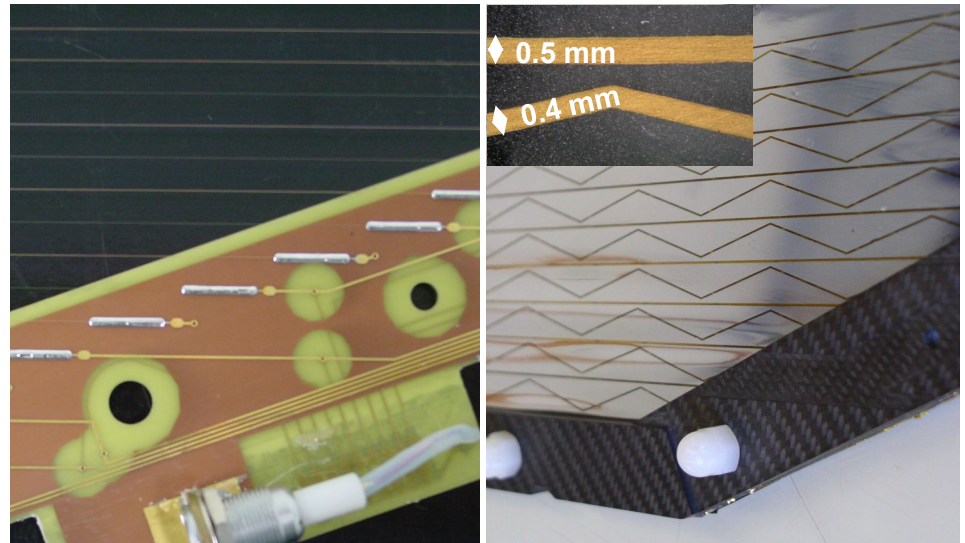
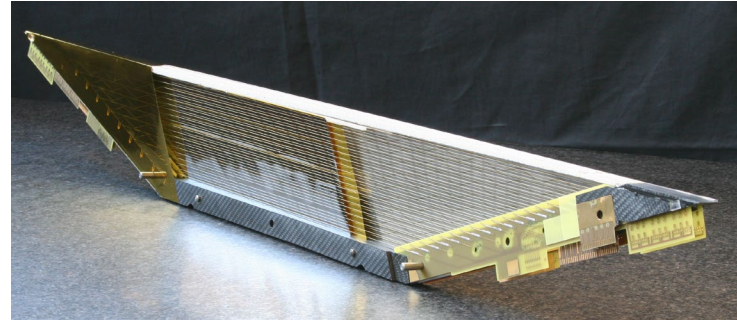
- designed to measure 52.8 MeV  $e^+$  (achieved  $\sigma_E \approx 330$  keV)
  - 16 individual drift chamber modules
  - aligned radially in half circle,  $10.5^\circ$  intervals
  - low multiple scattering contribution
    - $2.6 \cdot 10^{-4} X_0$  per module
    - $2.0 \cdot 10^{-3} X_0$  along  $e^+$  track
  - filling gas He/C<sub>2</sub>H<sub>6</sub> (50/50)
  - operated in Helium atmosphere
  - operated in B-field, 0.5 - 1.26 T
  
- mechanics
  - 1m long, V-shaped/ open trapezoidal geometry
  - carbon fibre frames
  - two (staggered) detector planes per module to resolve ambiguities
  - carbon fibre support structure (DC modules, HV/LV cables, gas tubes, etc.)



Hildebrandt, NIM A623, 111 (2010)  
 Adam *et al.*, EPJ C 73(4) 2365 (2013)

# Drift Chamber System @ MEG

- wiring
  - 25  $\mu\text{m}$  Ni80/Cr20 wires (2.2 k $\Omega$ /m)
  - 50  $\mu\text{m}$  Cu98/Be2 wires
- soldering
  - low-temperature tin (w/o rosin)
  - common flux
- cathode
  - 12.5  $\mu\text{m}$  polyamide foil
  - $\sim$ 250 nm sputtered aluminium coating
  - Vernier pattern ( $\lambda = 5$  cm, 47.5  $\Omega$ /m)
  - wet etching process
- gluing and sealing
  - Araldite AY 103-1, HY 991
  - ThreeBond 1533D (Silyl-based polymer)



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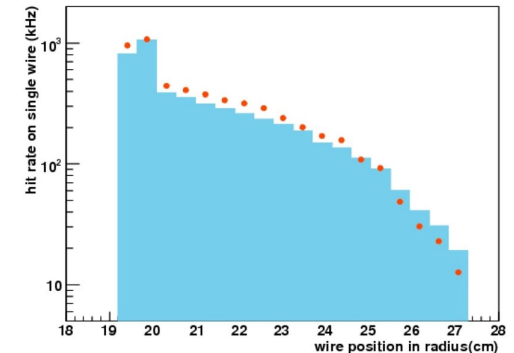
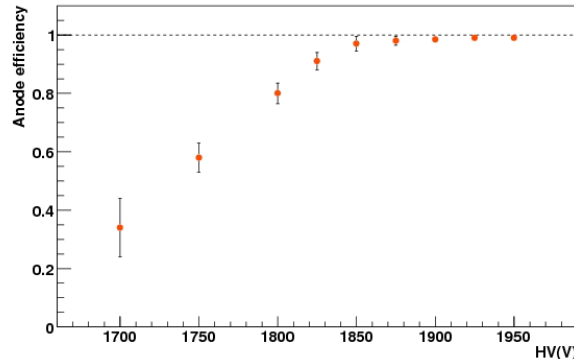
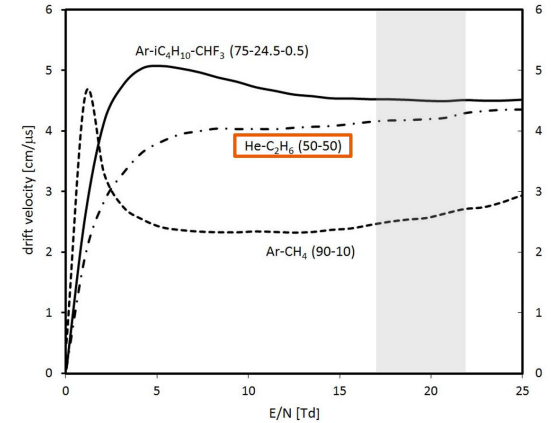
# Filling Gas and Operation Parameters

- filling gas
  - He/C<sub>2</sub>H<sub>6</sub> (50/50)
  - high, saturated  $v_d \sim 4 \text{ cm}/\mu\text{s}$ , small  $\alpha_{\text{Lorentz}} < 8^\circ$
  - He:  $X_0/\rho = 64 \text{ 000 cm}$ , but: low breakdown voltage
  - C<sub>2</sub>H<sub>6</sub>: good quenching properties, but: risk of polymerisation
- gas system
  - stainless steel, Swagelok fittings, polyurethane
- electron amplification
  - $E \approx 5.2 \text{ kV}/\text{cm} \approx 20 \text{ Td}$
  - electron amplification:  $\sim 5 \cdot 10^5$
- particle rate
  - up to 30 kHz/cm
- accumulated charge
  - up to 1 C/cm/8months

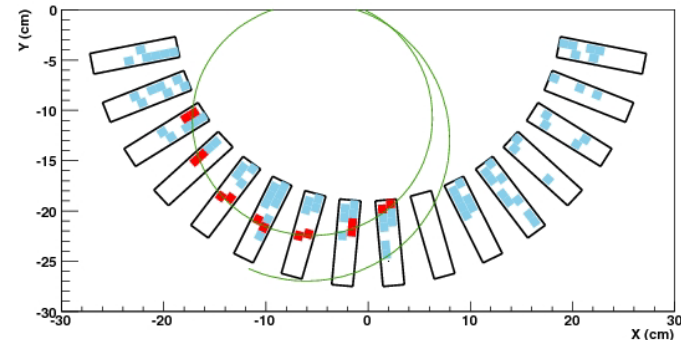
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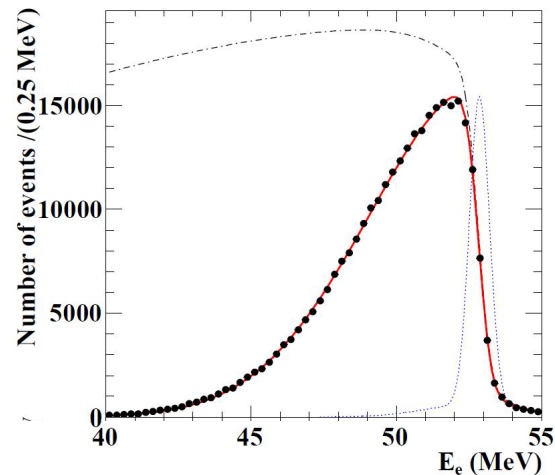
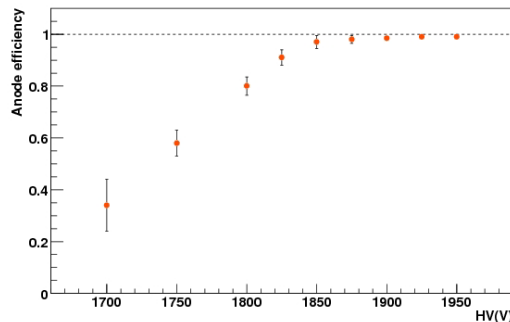
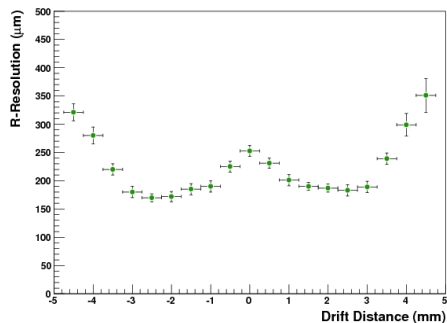
Hildebrandt



- operation
  - initial problems (2007/08) with HV stability due to
    - sealing of HV connections in outer Helium atmosphere and
    - «helium pocket»
  - anode and cathode aging phenomena
- performance (resolution  $\sigma$ )
  - energy  $\sim 330$  keV (@52.8 MeV)
  - angular  $\sim 8.5$  mrad in  $\theta$ ,  $\sim 7.7$  mrad in  $\phi$



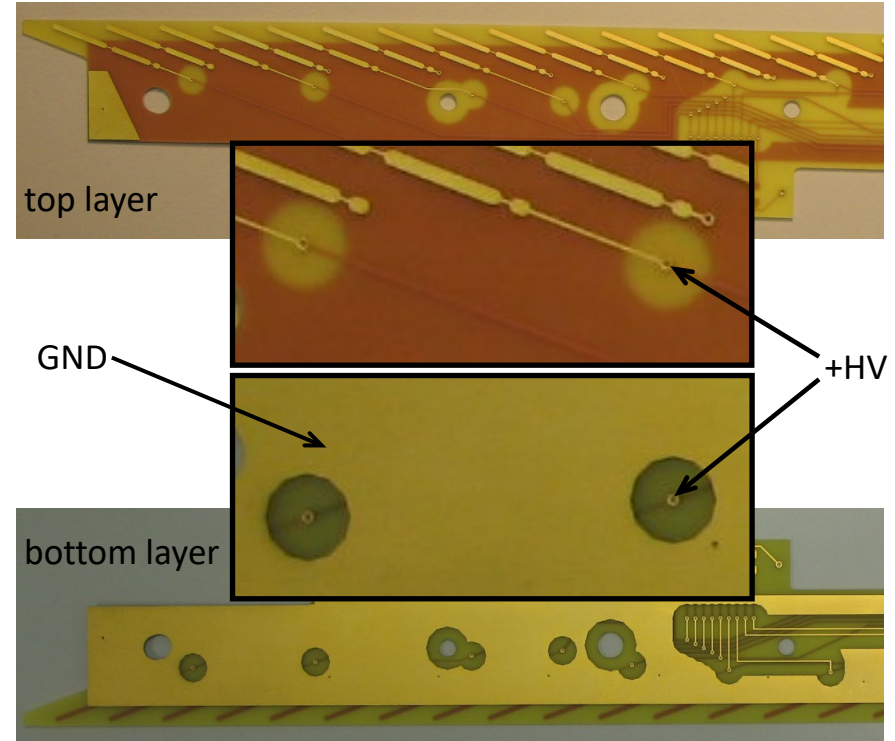
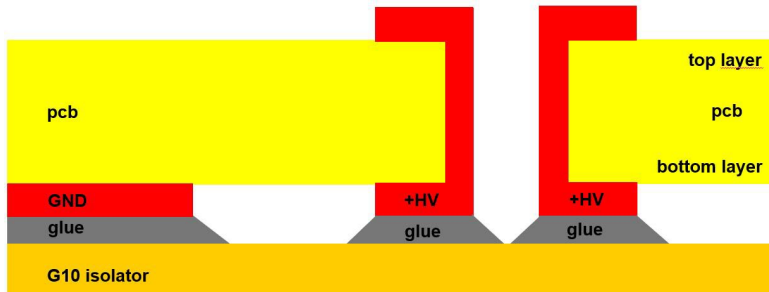
Resolution vs. Drift Distance





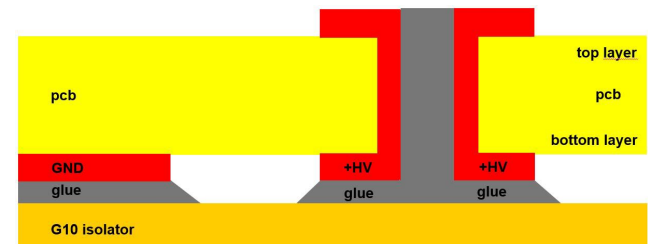
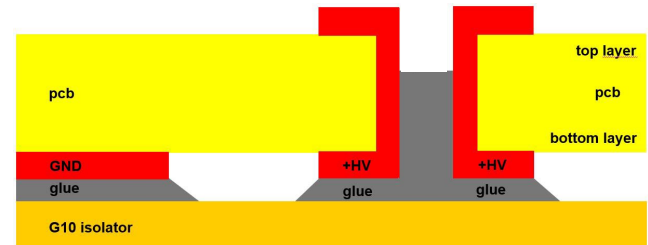
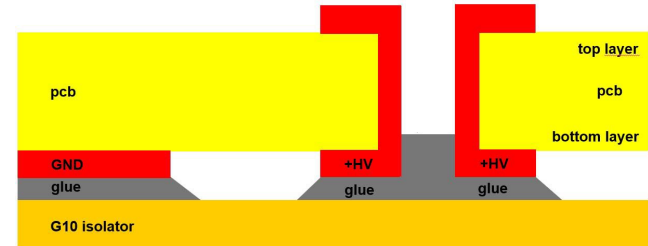
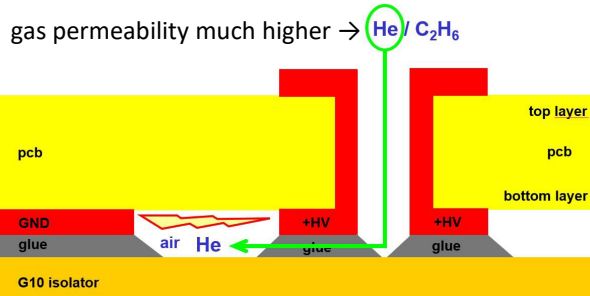
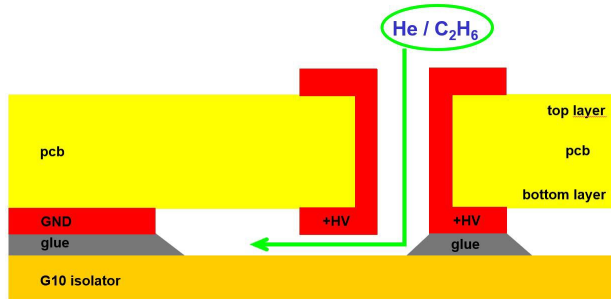
# «Helium Pocket»

- degradation of drift chamber performance
  - occurred within first weeks of operation
  - frequent HV trips
  - operation voltage continuously decreasing
  - individual timescale for different dc modules
- “helium pocket”
  - gas volume enclosed by HV and GND
  - He from filling gas penetrated in this gas volume
  - increasing He concentration led to decreasing breakdown voltage



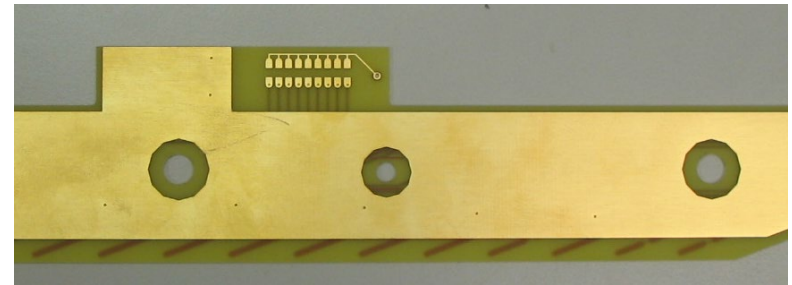
# «Helium Pocket»

- individual timescales of performance degradation
    - within few weeks
    - within few months
    - never
- } → depending on thickness of glue that needs to be penetrated by Helium

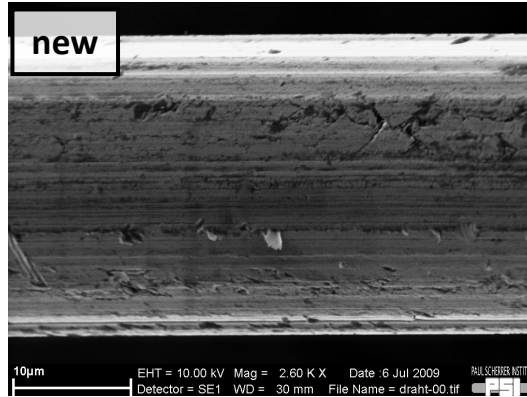


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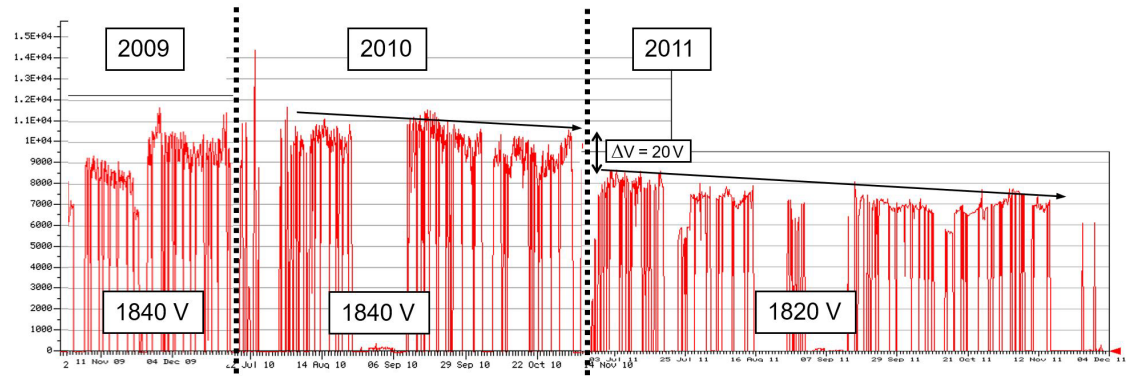
- confirmation of hypothesis
  - drift chamber module without outer cathode hood
  - operated in He and He/C<sub>2</sub>H<sub>6</sub> atmosphere
  - after 65 days of operation: observation of discharge
  
- solution
  - new layout of wire pcb
  - no HV traces on bottom layer
  - individual layers for HV and GND
  - “tapped blind vias” to connect only appropriate layers
  
- newly build drift chamber modules worked in long-term operation
  - occurrence of long-term aging phenomena



- Ni/Cr (80/20) 25 $\mu$ m
- data sheet
  - Ni balance
  - Cr 18 - 20 %
  - Si 1.5 %
  - Al 1000 ppm
  - Fe 2000 ppm
  - Mn 2000 ppm

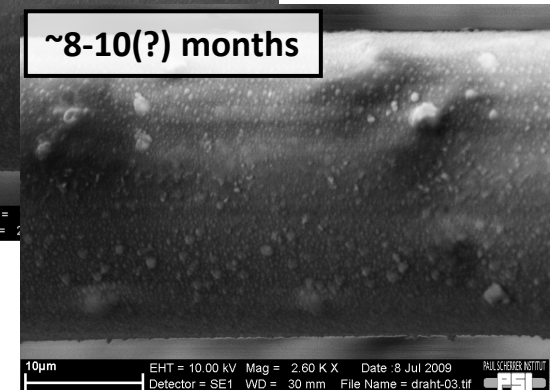
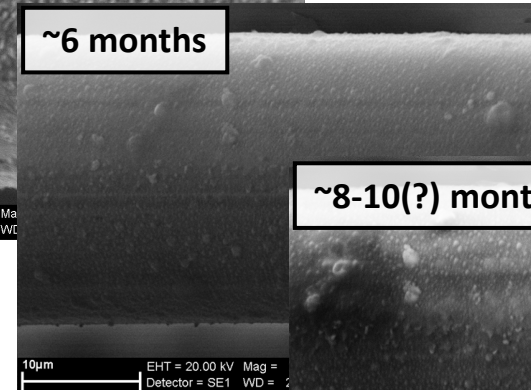
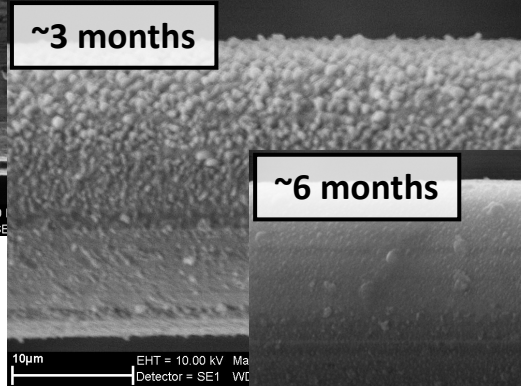
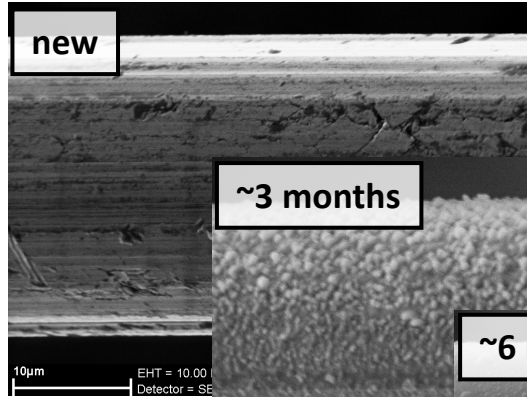


- scanning electron microscope (SEM)  
(S. Ritter, PSI)





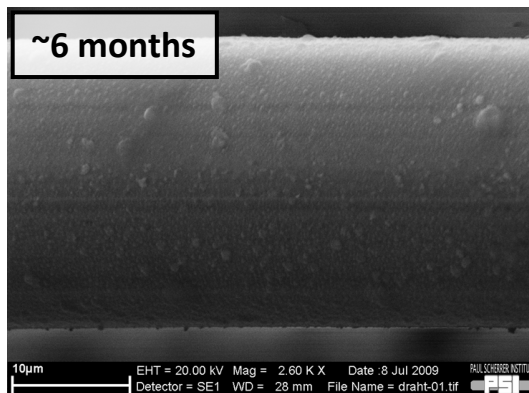
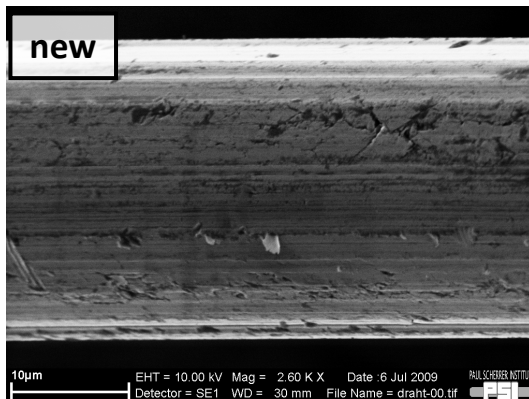
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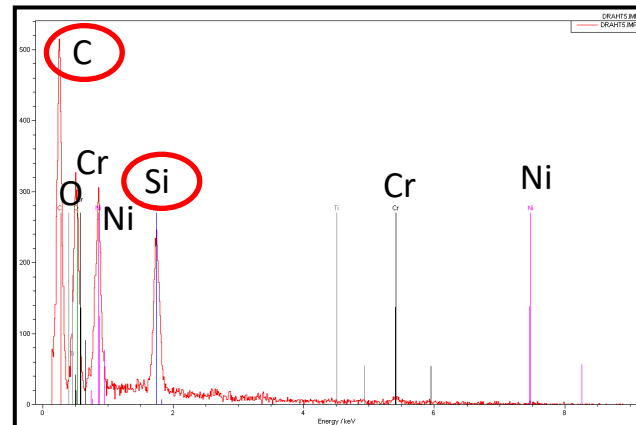
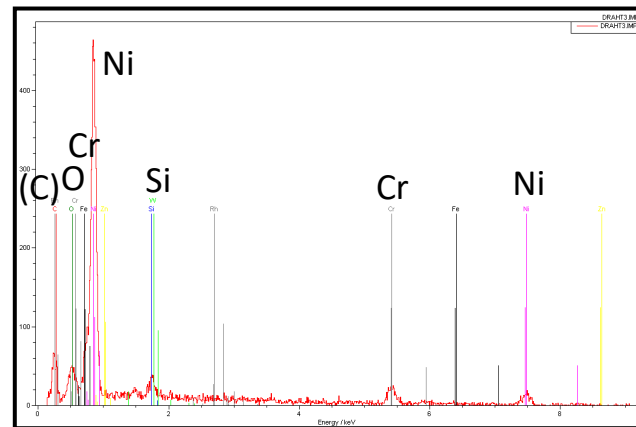
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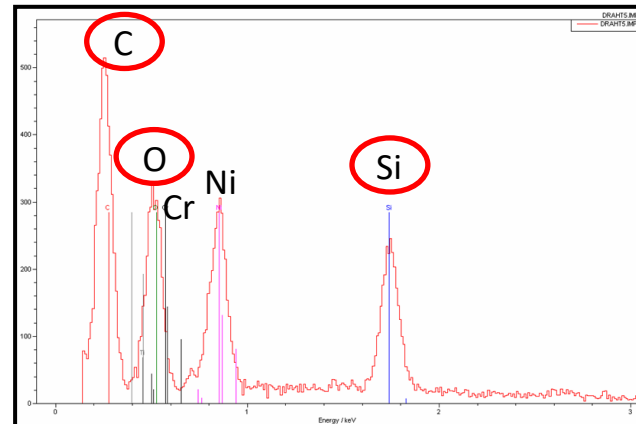
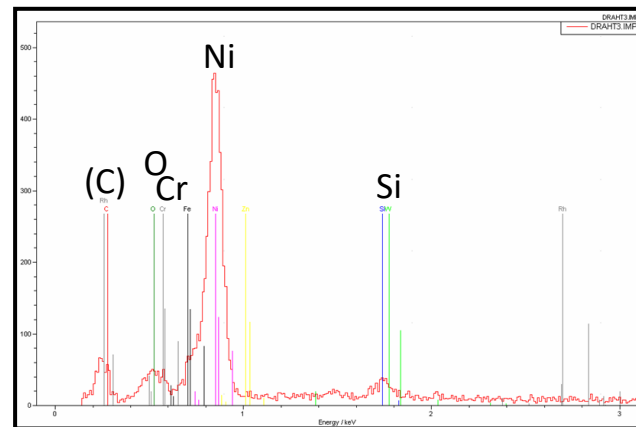
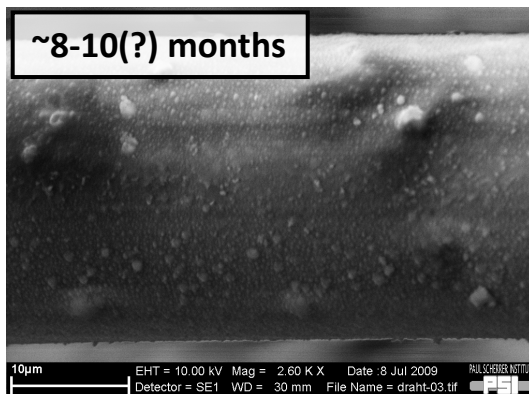
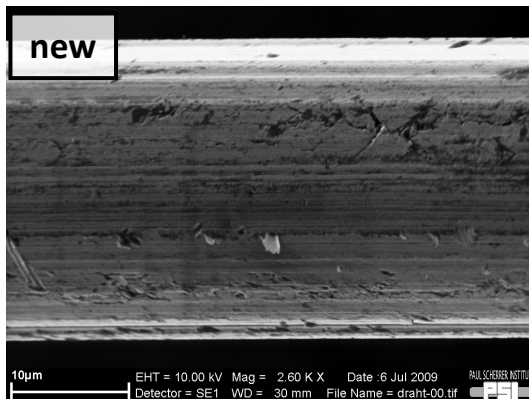
- energy-dispersed x-ray spectroscopy (EDX)  
(S. Ritter, PSI)



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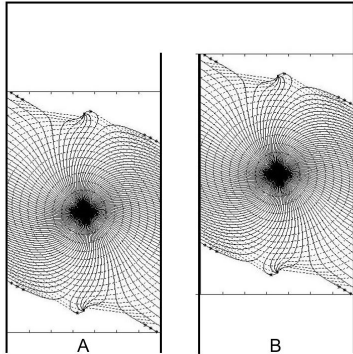
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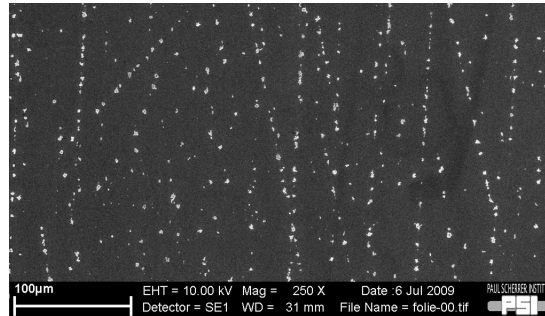
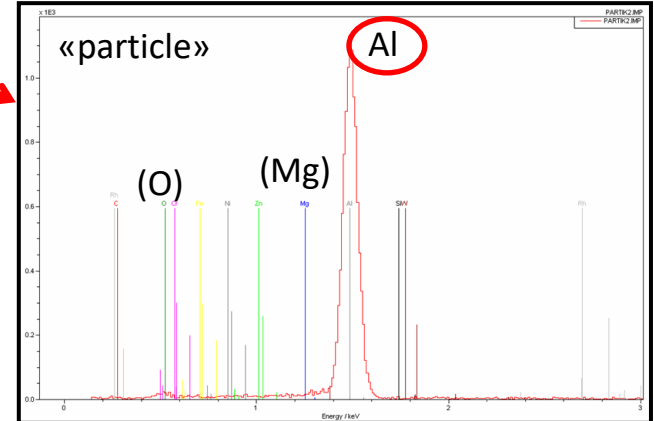
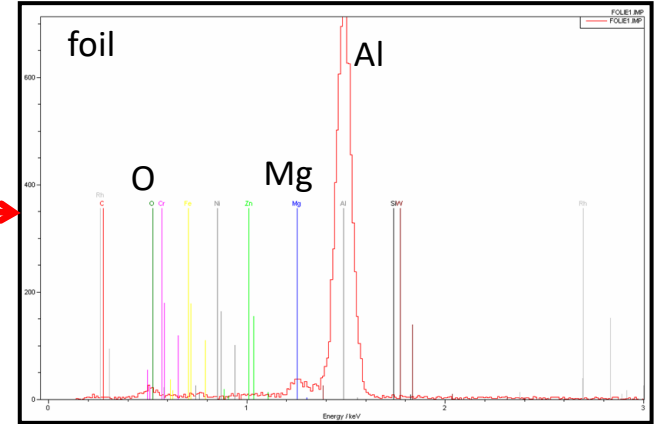
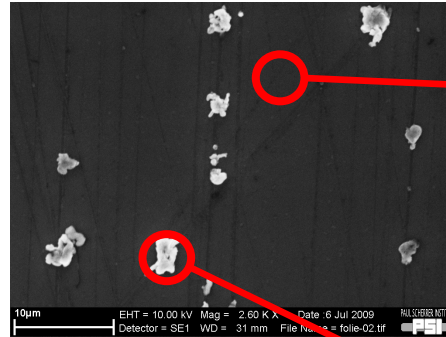
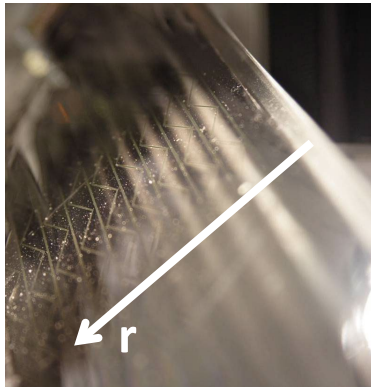
- scanning electron microscope (SEM)  
(S. Ritter, PSI)
- energy-dispersed x-ray spectroscopy (EDX)  
(S. Ritter, PSI)

- aluminium peeling off
  - effected region with sharp edges
  - not symmetric to anode wire, shifted due to 'rotation' of E-field in  $E \times B$  configuration?
  - feedback manufacturer: maybe due to missing chromium underlayer

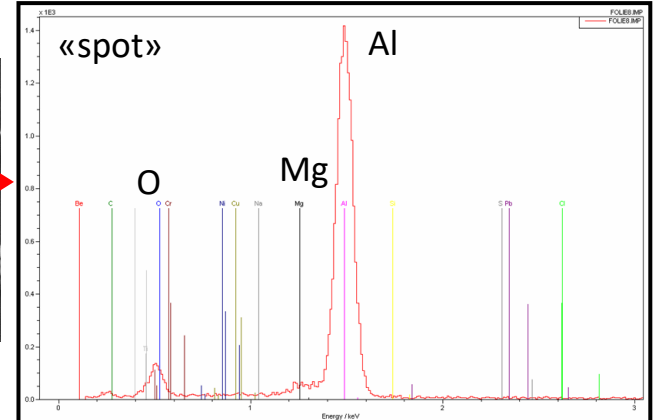
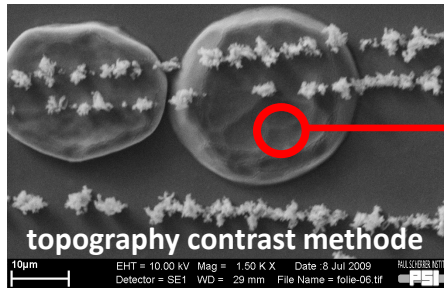
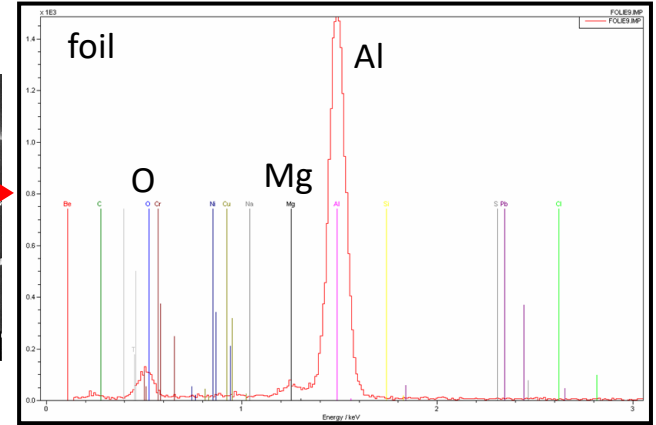
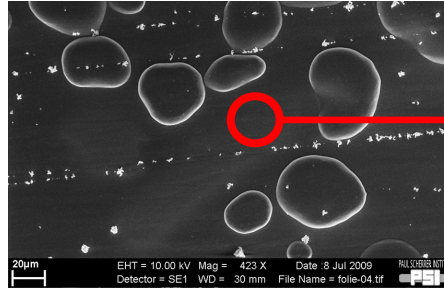




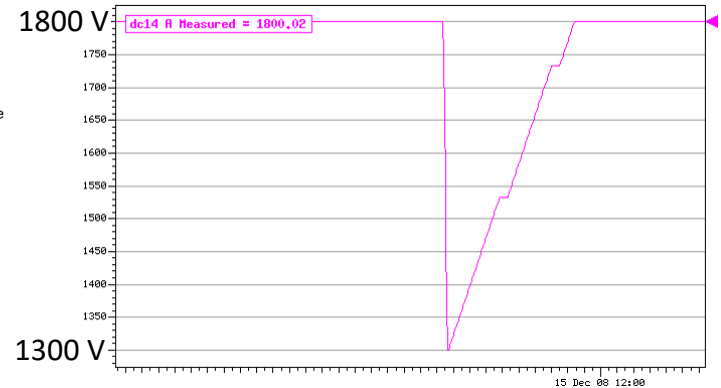
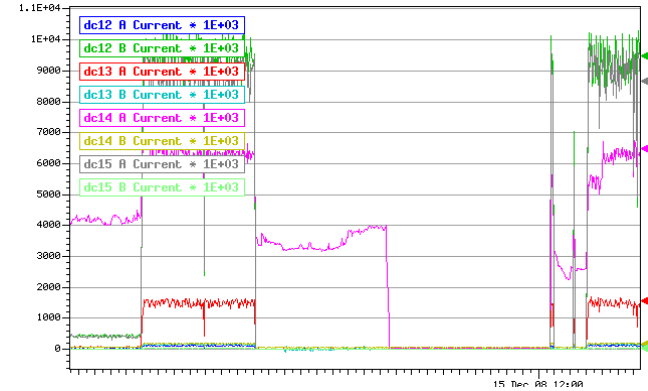
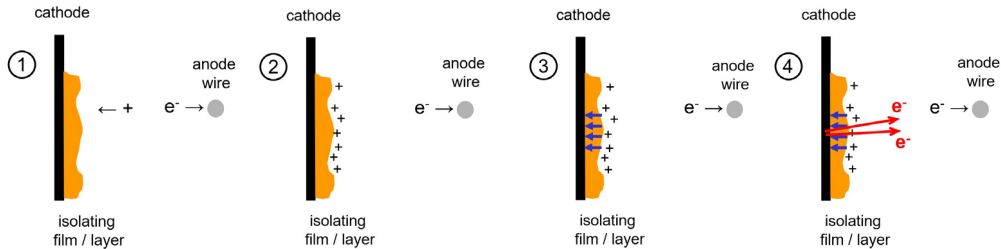
- white “shadow”
  - intensity decreasing with increasing  $r$
  - not continuous in  $r$ , but separated stripes
  - not symmetric to anode wire
  - with magnification: “particles” perfectly aligned in lines
  - assumption: scratches seed for material coming up to the surface



- “spots”, “peaks”
  - effected region with sharp edges
  - slightly extended at etched gaps
  - not symmetric to anode wire
  - with magnification: “bubbles”(?)
  - precursor for peeling off?

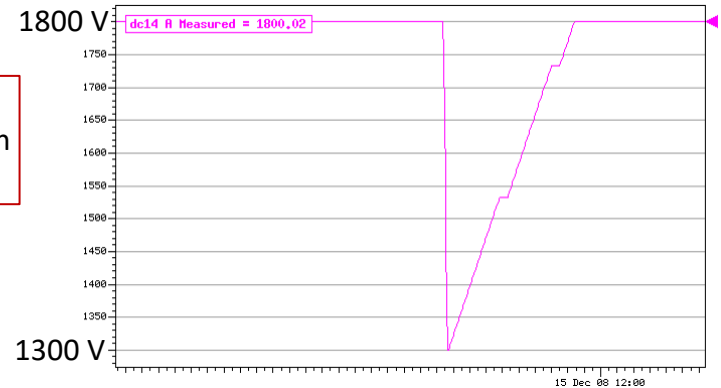
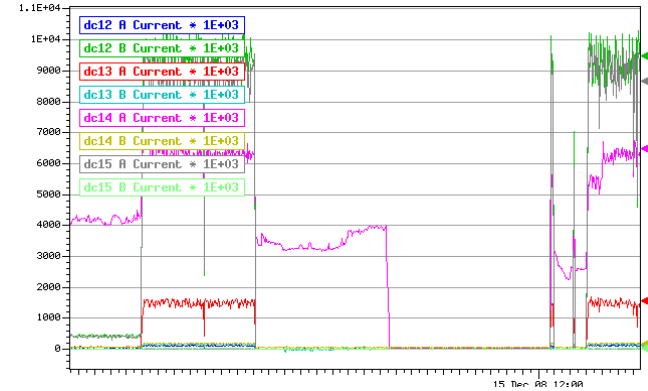


- remaining current
  - current starts only during high-rate irradiation (not a surface current)
  - remaining current stays, even external irradiation finished
  - only when HV is reduced to 1300 V ( $\alpha_{\text{Townsend}} = 0$ ) remaining current dies away
  
- Malter effect (“thin film field emission”)
  - Louis Malter, Phys.Rev. 50 (1936) 48-58



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- potential insulating thin film on cathode
  - remaining photoresist
  - traces of glue
  - fingerprints
  - avalanche-produces polymers from filling gas ( $\text{C}_2\text{H}_6$ )
  - gas pollutants
  - insulating deposits left from sparks

→ improved cleaning procedure by manufacturer improved operation of newly build dc modules





## Summary

- The drift chamber system of the MEG experiment faced quite some challenges: He, C<sub>2</sub>H<sub>6</sub>, aluminium, high gain, high rate
- Initial HV instabilities due to “helium pocket” fixed with new design of wire pcb.
- Long-term operation showed ‘classical’ and ‘textbook-like’ anode wire and cathode aging.

